

Beamtests of HPK/KEK n^+ -in-p pixel sensors for ATLAS HL-LHC upgrade inner tracker

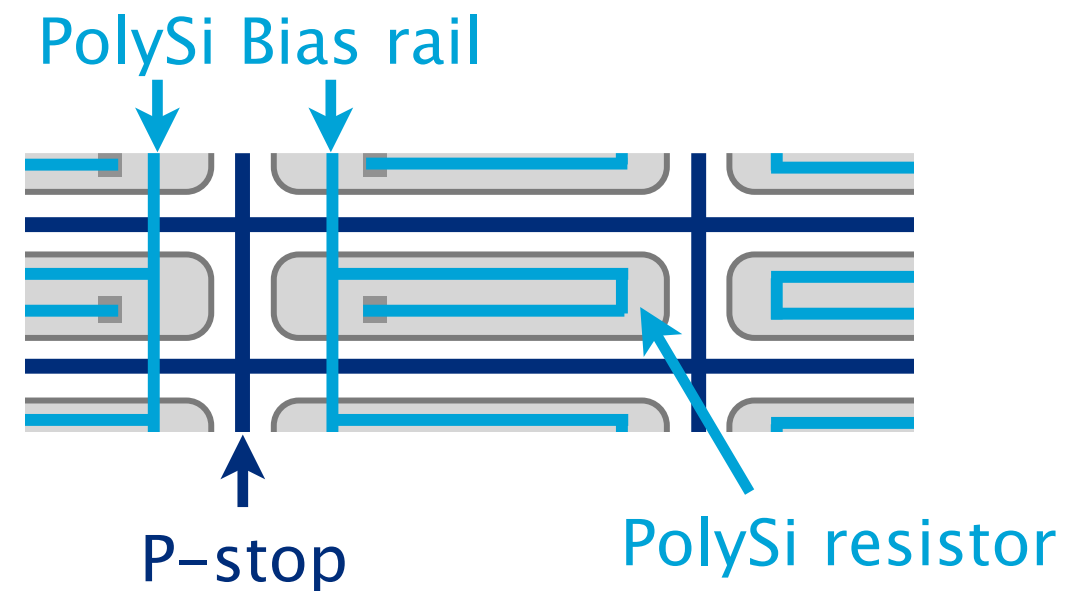
Daiki Yamaguchi (Tokyo Tech.)

on behalf of

ATLAS-J Silicon Group, ATLAS PPS Collaboration, and
Hamamatsu Photonics K.K

ATLAS-J Pixel development

- Develop **n⁺-in-p planar pixel sensors** for ATLAS upgrade, collaborating with Hamamatsu Photonics K.K
- Focus on:
 - **Uniformity of high hit efficiency even after irradiation**
- **Optimize the pixel structures** (See Nobu’s talk)
- Testbeams
 - DESY in Aug. 2013
 - DESY in Nov. 2013
 - DESY in Feb. 2014
 - SLAC in May 2014
 - (CERN in Oct. 2014)



Testbeam Analysis

■ Four analysis topics

1) Uniformity of hit efficiency for Non-irrad. sensors

- ▶ TB at DESY in Aug. 2013 & in Feb. 2014

2) Uniformity of hit efficiency for irrad. sensors

- ▶ TB at DESY in Nov. 2013 & in Feb. 2014

3) Performance of Long Staggered pixel

- ▶ TB at DESY in Aug. 2013

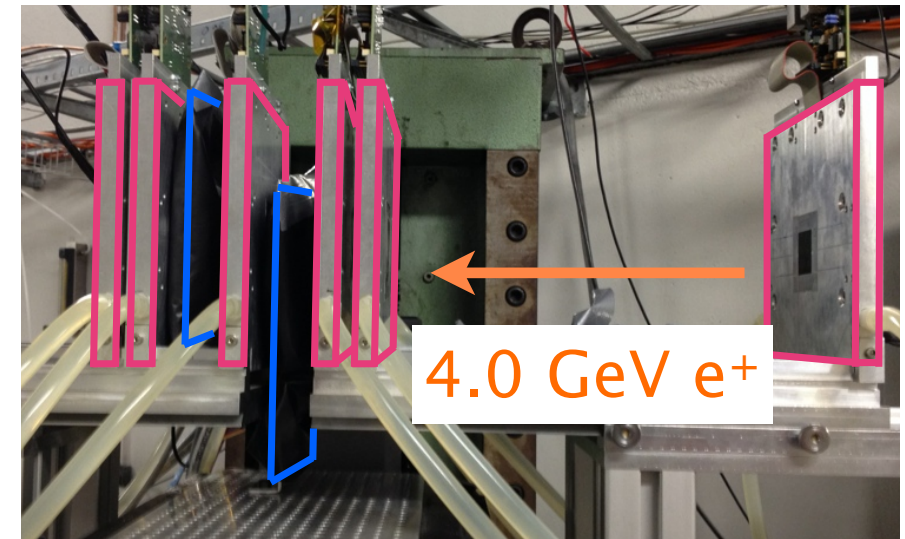
4) Performance in dense environment

- ▶ TB at SLAC in May 2014

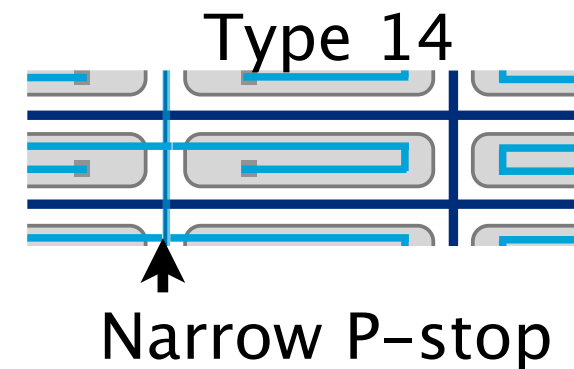
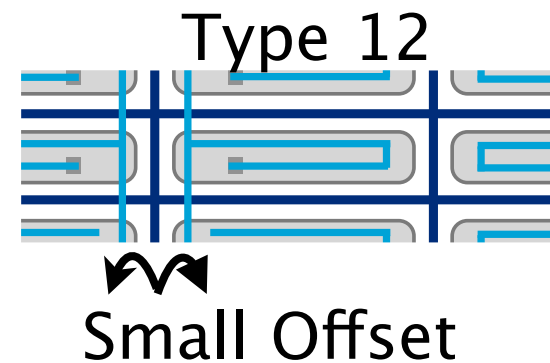
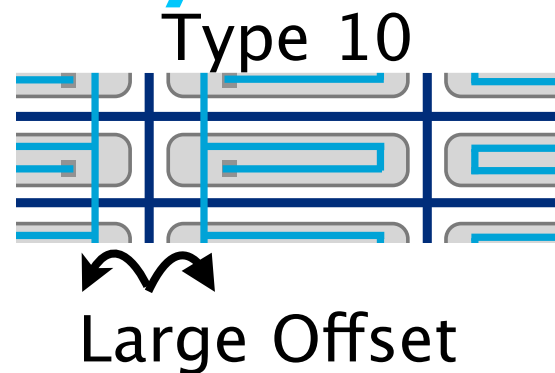
Non-irrad. sensors

- Testbeam at DESY in Feb. 2014
 - Located as close as possible
 - ▶ Pointing Resolution: $\sim 6 \mu\text{m}$

- Test samples

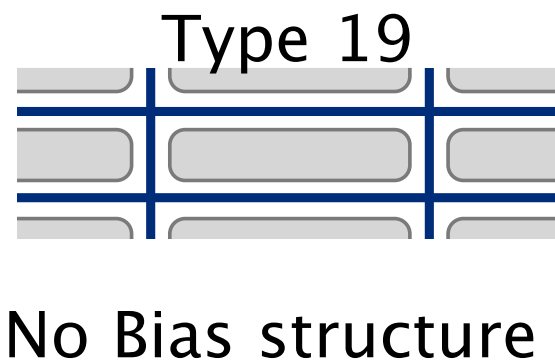


- Poly-Si Bias rail

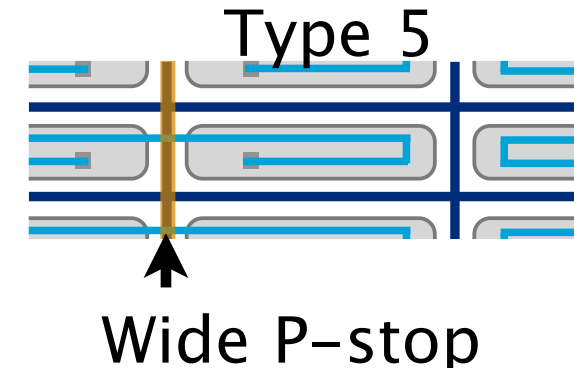
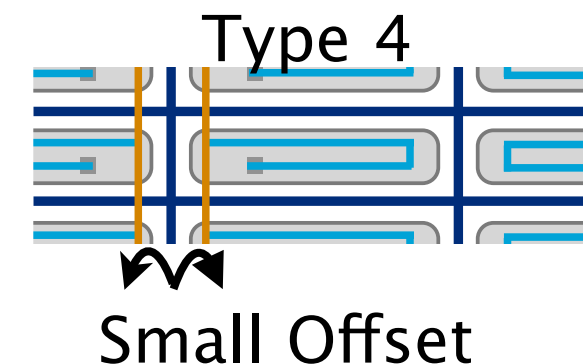


6 Telescopes
2 DUTs

- No Bias rail



- Al Bias rail



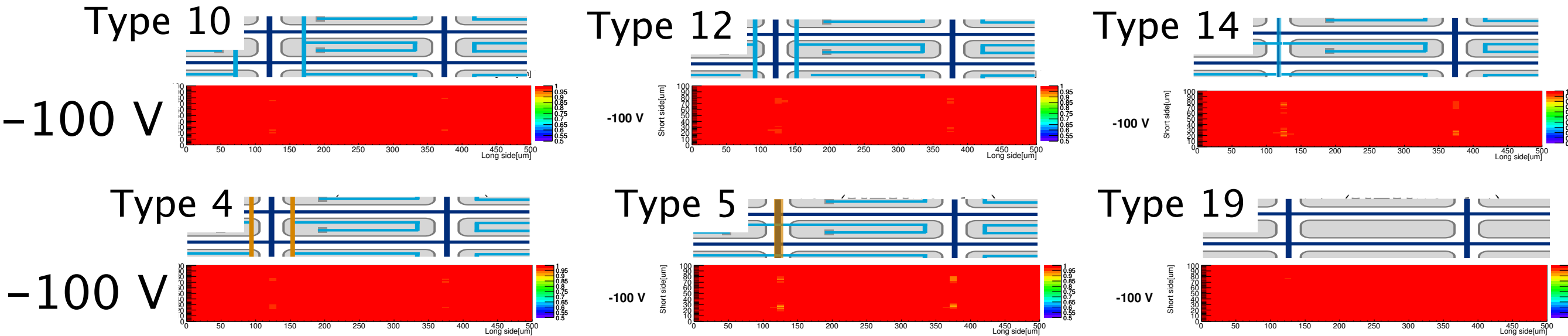
Non-irrad. sensors

Overall Hit efficiency

Sensor Type	Hit Efficiency at 15 V [%]	Hit Efficiency at 100 V [%]
Type 10	$88.087^{+0.034}_{-0.034}$	$99.844^{+0.004}_{-0.005}$
Type 12	$88.771^{+0.039}_{-0.039}$	$99.807^{+0.005}_{-0.005}$
Type 14	—	$99.721^{+0.006}_{-0.006}$
Type 4	—	$99.688^{+0.007}_{-0.007}$
Type 5	—	$99.728^{+0.010}_{-0.010}$
Type 19	—	$99.677^{+0.008}_{-0.008}$

more than 99%

Hit Efficiency pixel map



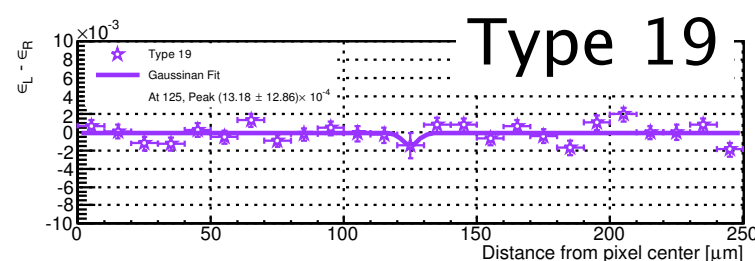
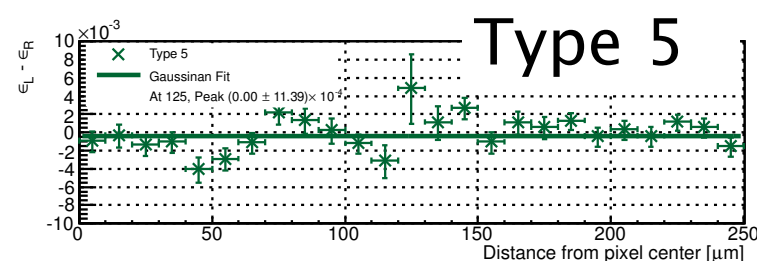
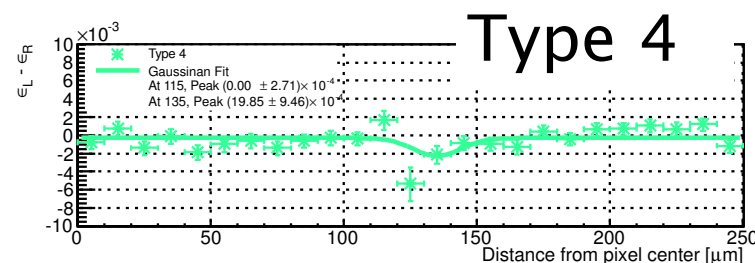
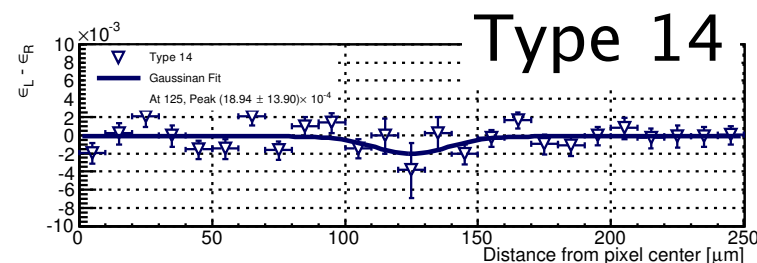
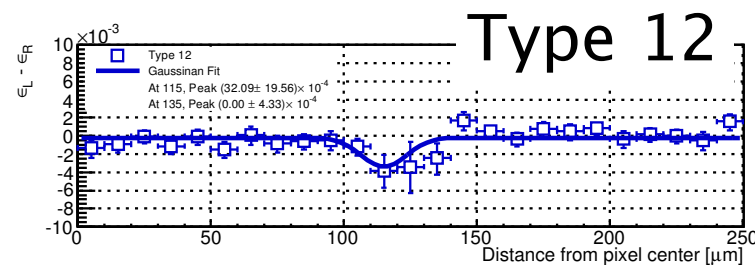
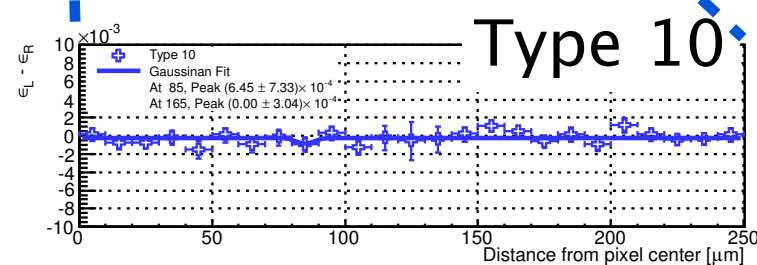
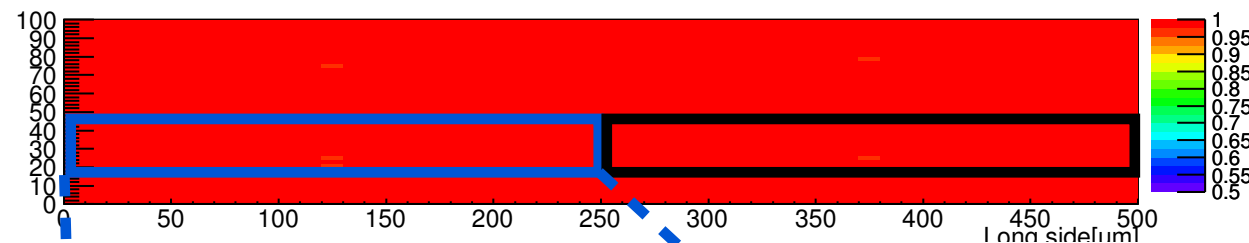
Uniform hit efficiency for all non-irrad. sensors

Non-irrad. sensors

Influence by Bias rail



Hit Eff. in blue – Hit Eff. in black
= influence by bias rail



Project hit efficiency
pixel map to long side

Fit it by Gaussian

– Hit Efficiencies are not affected by the bias rail

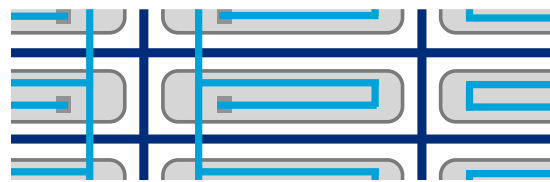
Irrad. sensors

6 Telescopes & 2 DUTs

- Testbeams at DESY
 - Multiple scattering
 - Pointing Resolution: $\sim 26 \mu\text{m}$

- Test samples

Large Offset
(Type 10)



Large Offset

- Fluence:
 $5 \times 10^{15} [\text{n}_{\text{eq}} \text{cm}^{-2}]$
Thickness: $320 \mu\text{m}$
- Fluence:
 $5 \times 10^{15} [\text{n}_{\text{eq}} \text{cm}^{-2}]$
Thickness: $150 \mu\text{m}$

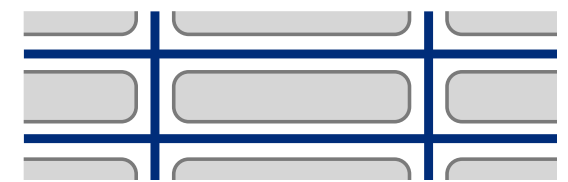
Wide P-stop
(Type 13)



Wide P-stop

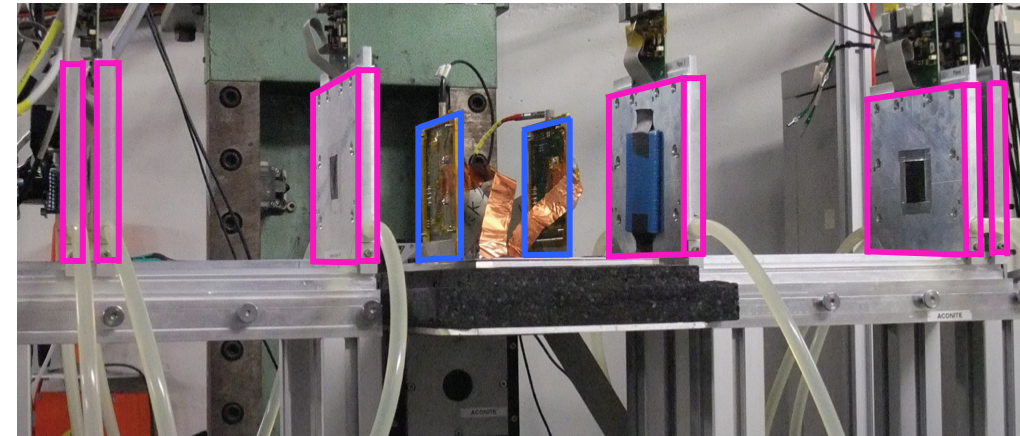
- Fluence:
 $3 \times 10^{15} [\text{n}_{\text{eq}} \text{cm}^{-2}]$
Thickness: $320 \mu\text{m}$

No bias
(Type 19)



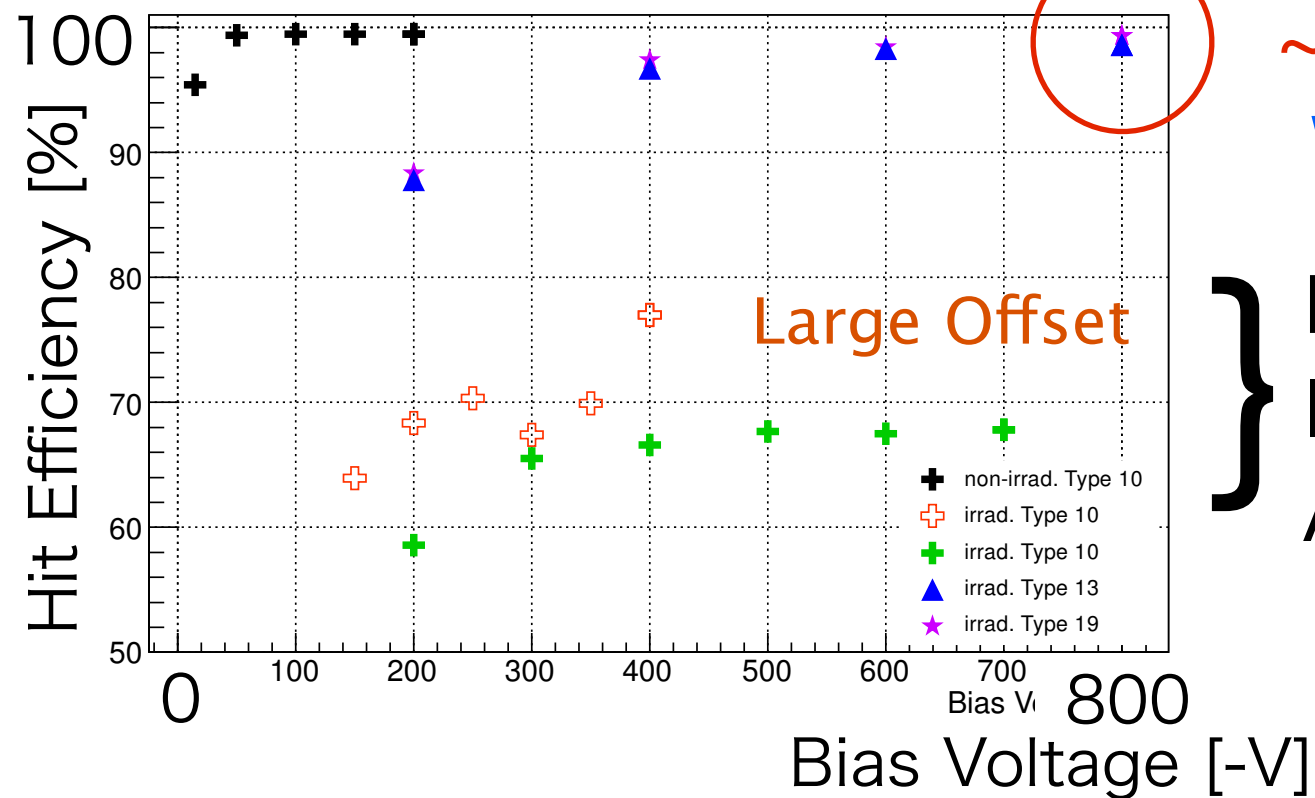
No Bias structure

- Fluence:
 $3 \times 10^{15} [\text{n}_{\text{eq}} \text{cm}^{-2}]$
Thickness: $320 \mu\text{m}$



Irrad. sensors

Overall Hit Efficiency



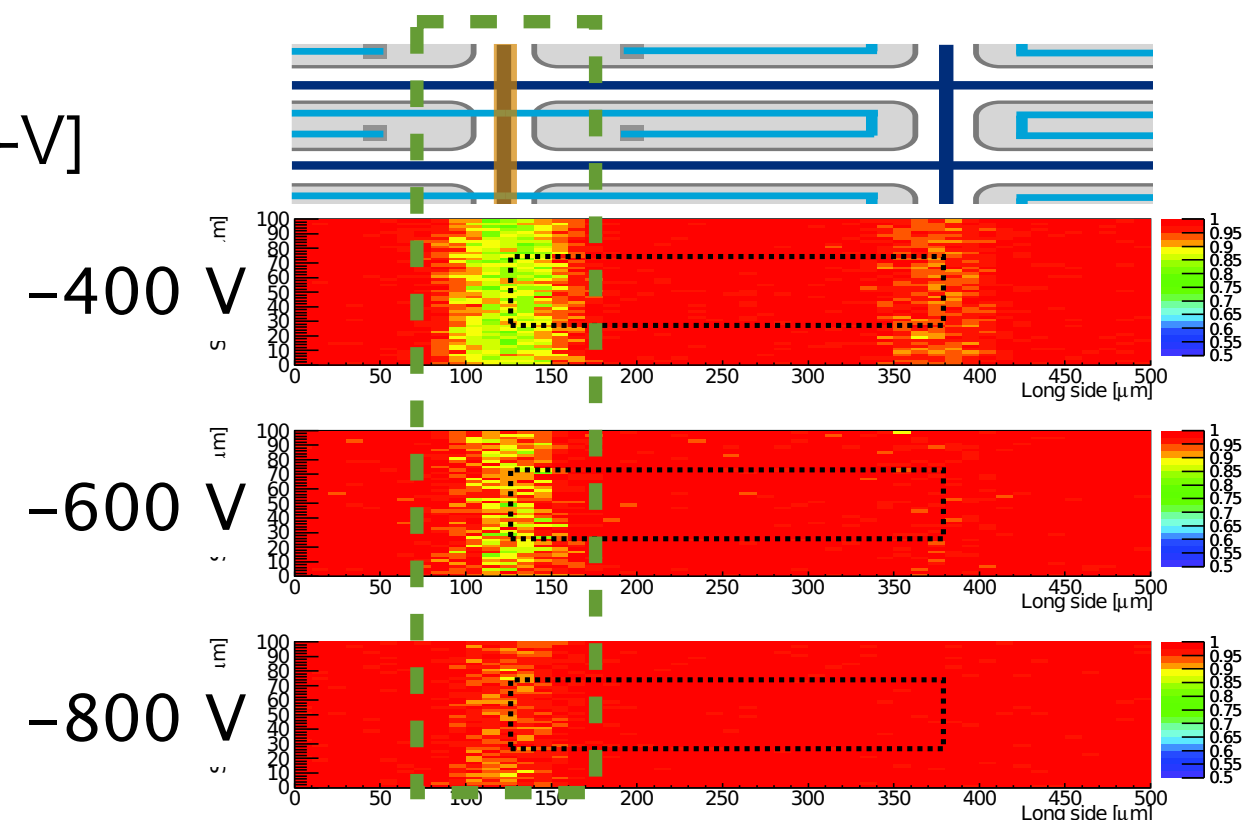
~99% at -800 V

Wide P-stop, No bias

No reference planes available
Issue about sync. of signals
Abs. values are not reliable...

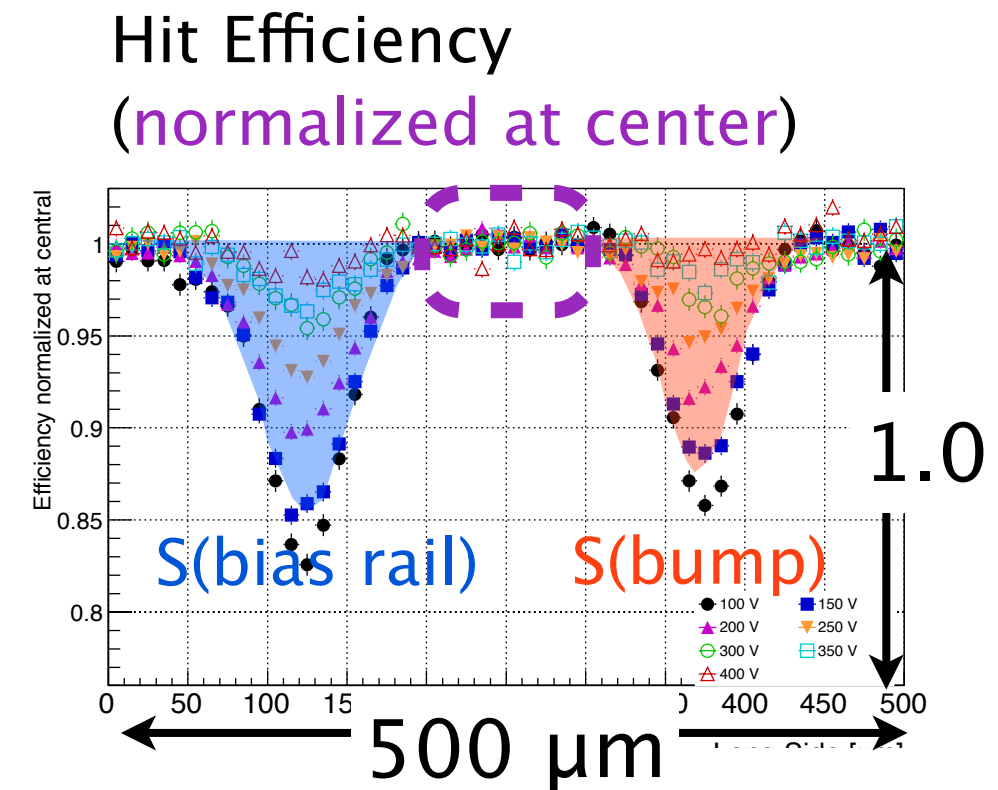
Hit Efficiency Pixel map

- Wide P-stop:
Hit Efficiency drops
under the bias rail
(but see the later slides)



Irrad. sensors

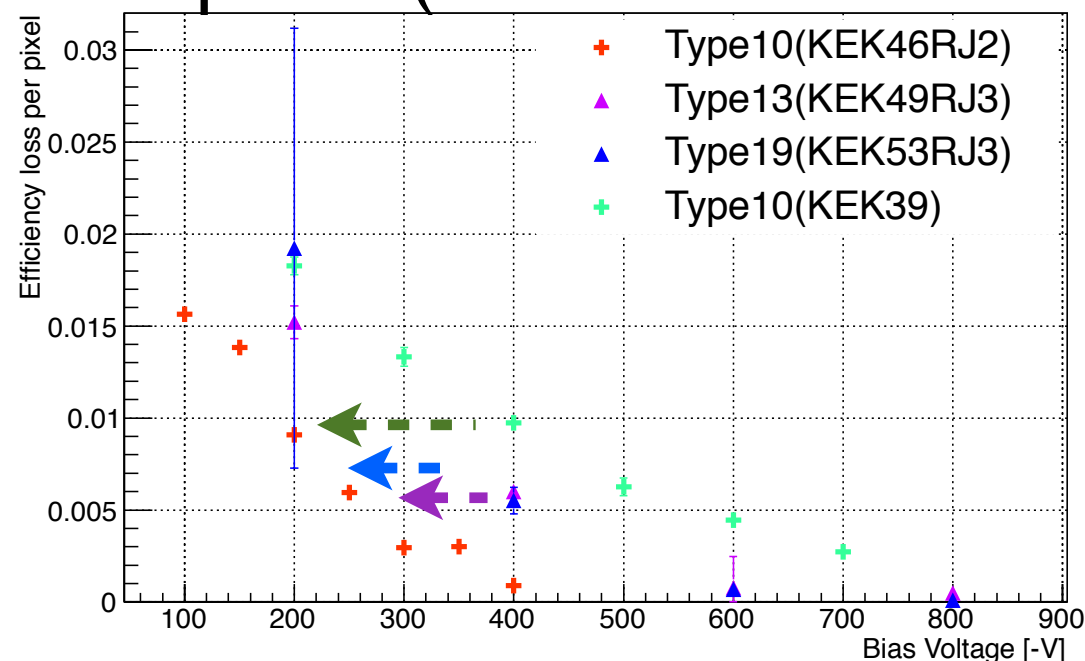
- Evaluate the hit eff. drop under the bias rail quantitatively
 - Hit Eff. pixel map is projected into long side
 - Normalize, Fit by Gaussian and calculate the area
- Efficiency Loss per pixel
 $= S / (1.0 \times 500 \mu\text{m})$
- But we have samples w/
different sensor thickness &
radiation fluences...



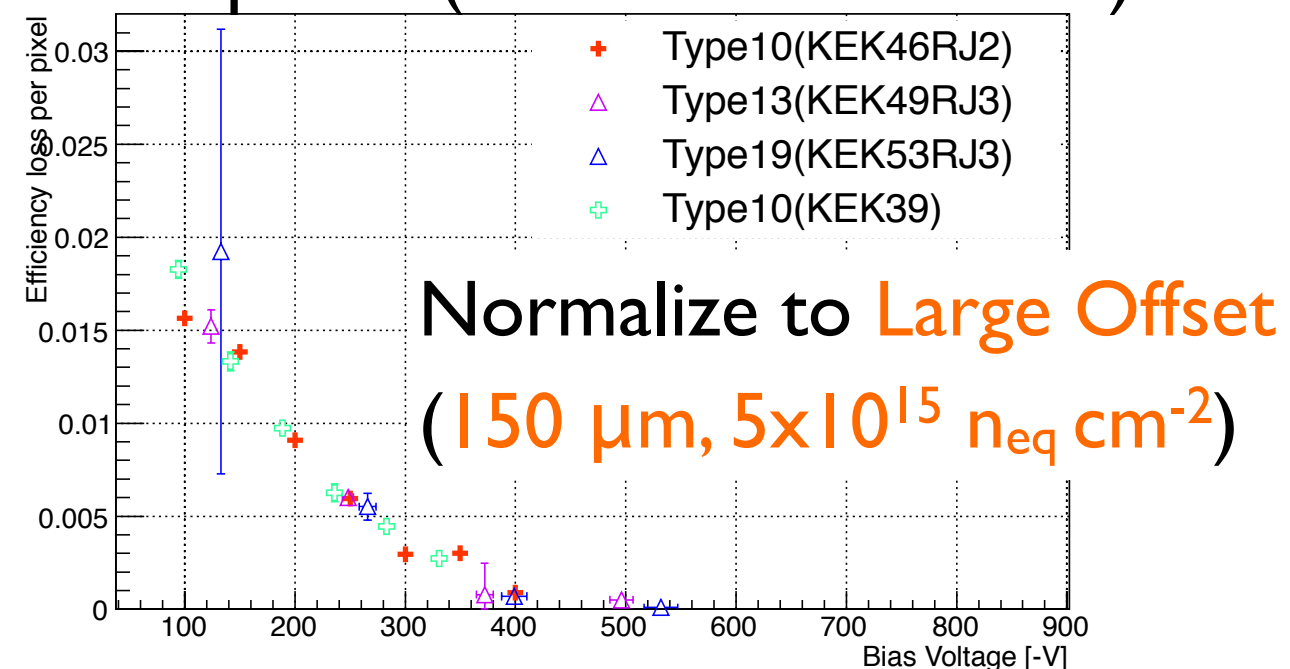
Thickness & Fluence Correction

- Take the differences of thickness & fluence into account
 - Approximately, fit bump side by an error function
 - Normalize to
Large Offset sensor with $150\text{ }\mu\text{m}$, $5 \times 10^{15}\text{ n}_{\text{eq}}\text{ cm}^{-2}$
 - calculate transfer function

Bump side (**before correction**)



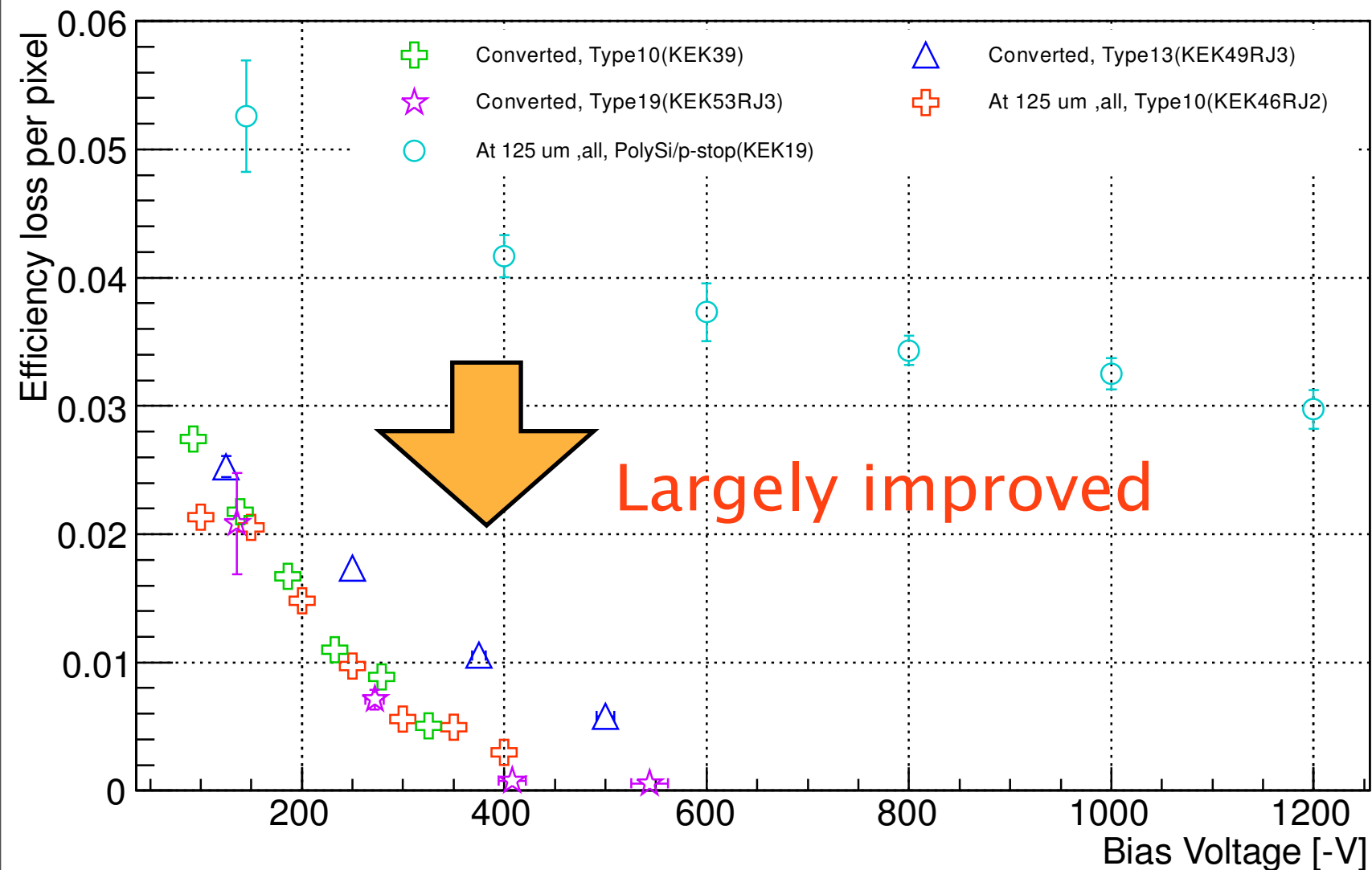
Bump side (**after correction**)



- Apply the transfer function to bias rail side

Irrad. sensors ($5 \times 10^{15} \text{ n}_{\text{eq}} \text{ cm}^{-2}$, $150 \text{ } \mu\text{m}$)

■ Efficiency loss per pixel under the bias rail

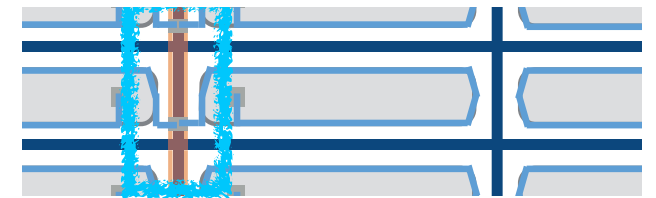


Eff. loss per pixel under the bias rail

No bias $\simeq$ Large Offset

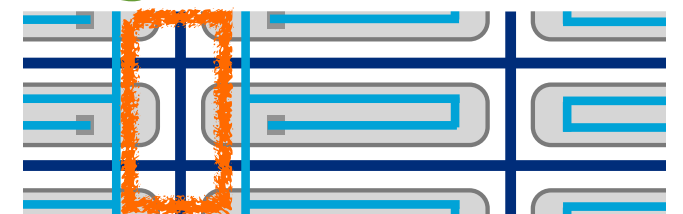
< Wide P-stop << Original

○ Original

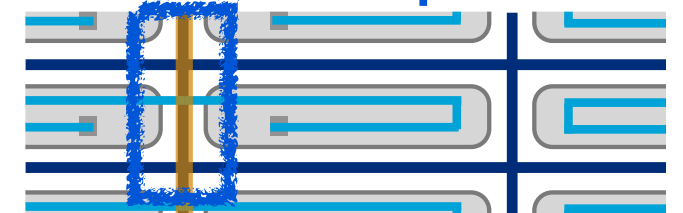


+ Large Offset

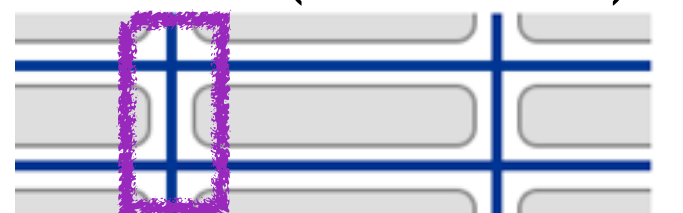
+ Large Offset(converted)



Δ Wide P-stop(converted)

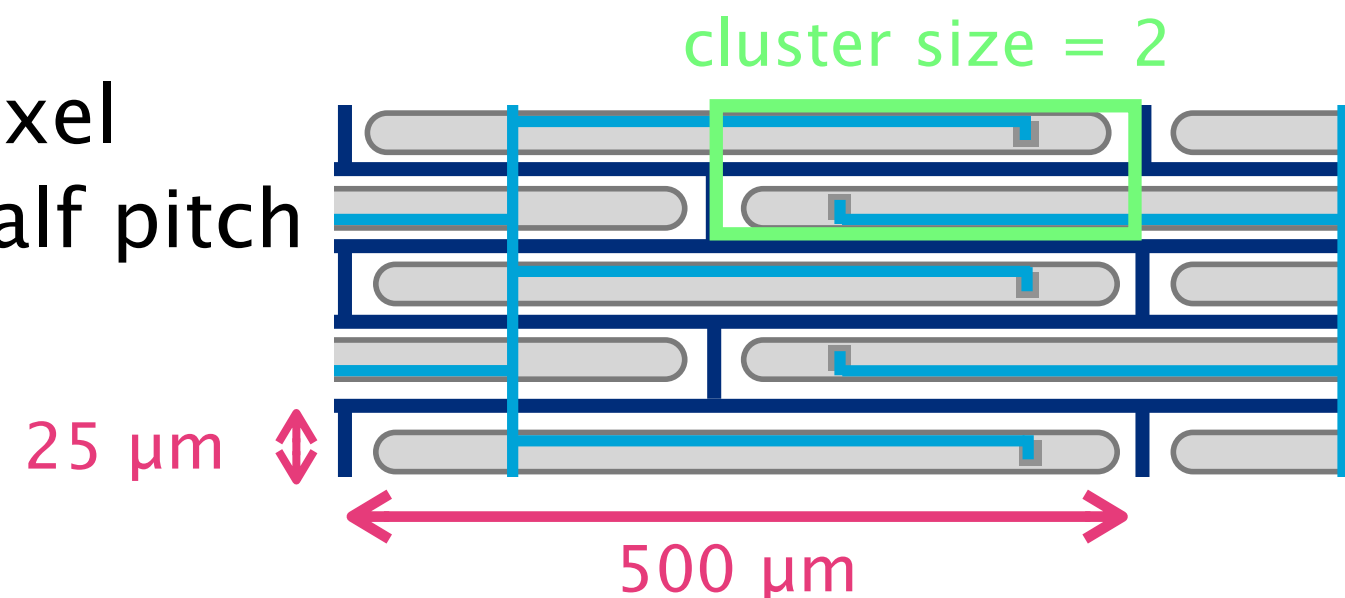


☆ No bias(converted)



Long Staggered Pixel

- "Long" = $25 \times 500 \mu\text{m}^2$ pixel
"Staggered" = Offset by half pitch



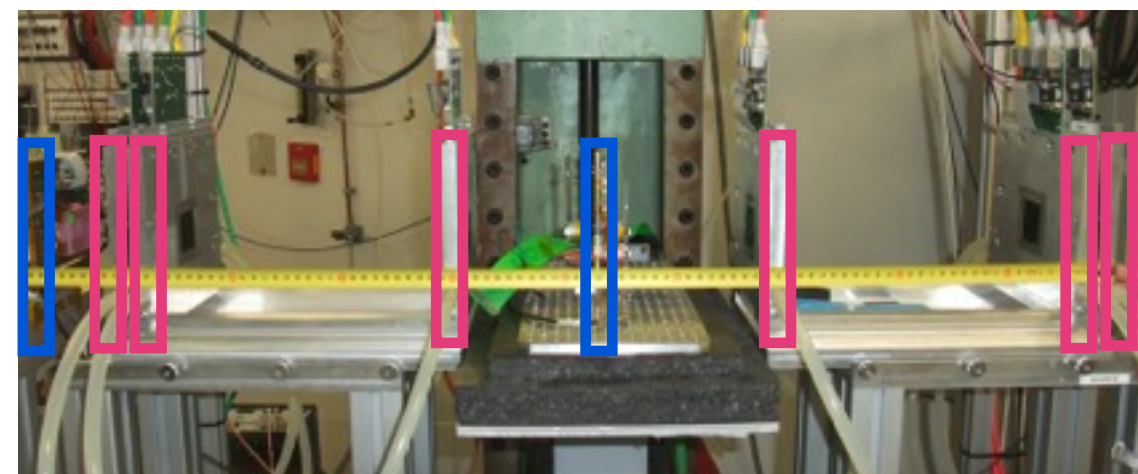
- Position resolution

- Short side: $25 \mu\text{m}$ pitch
better position resolution than $50 \mu\text{m}$ pitch
- Long side w/ clustering: $250 \mu\text{m}$ pitch
due to staggered geometry

- Testbeam at DESY in Aug. 2013

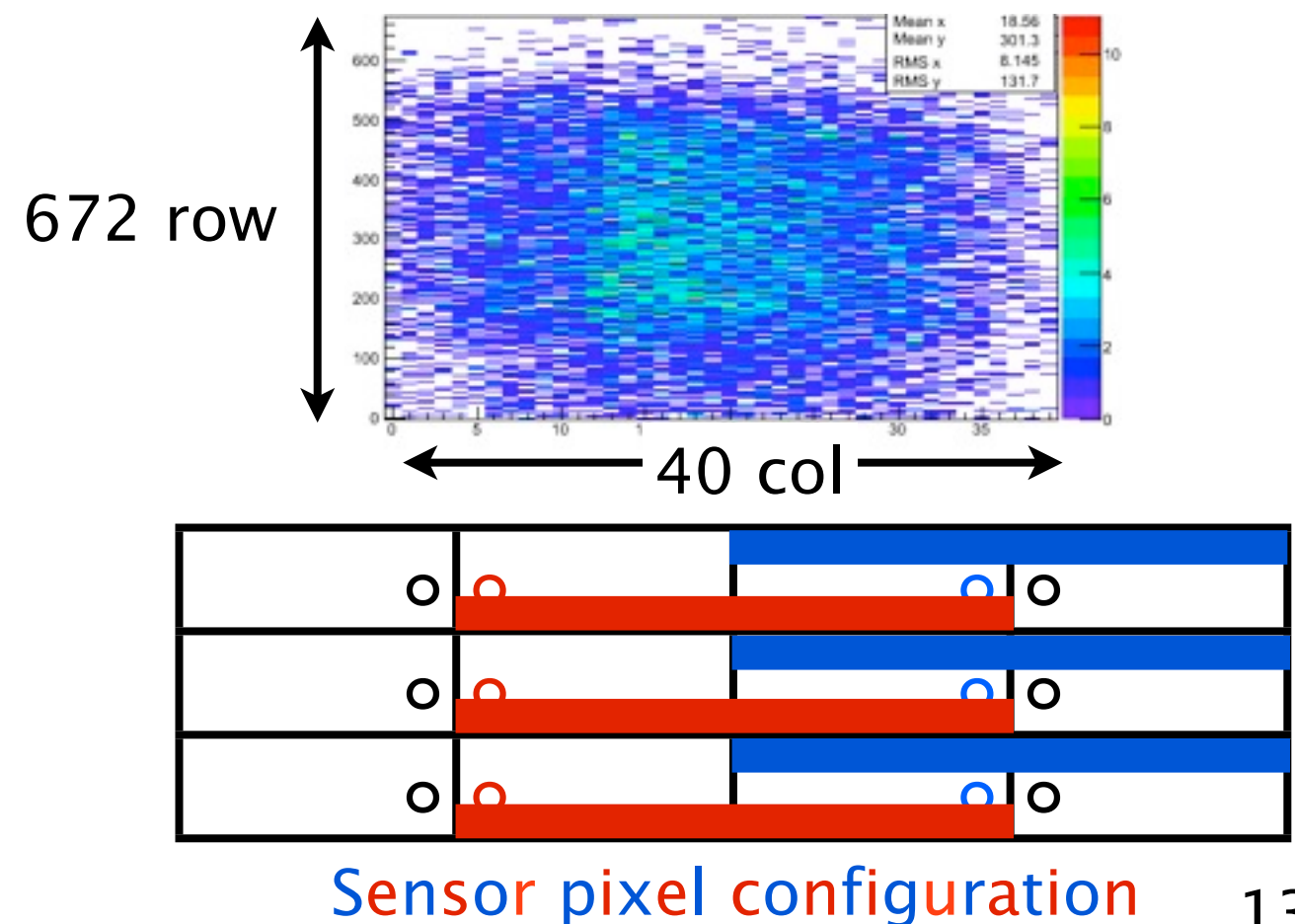
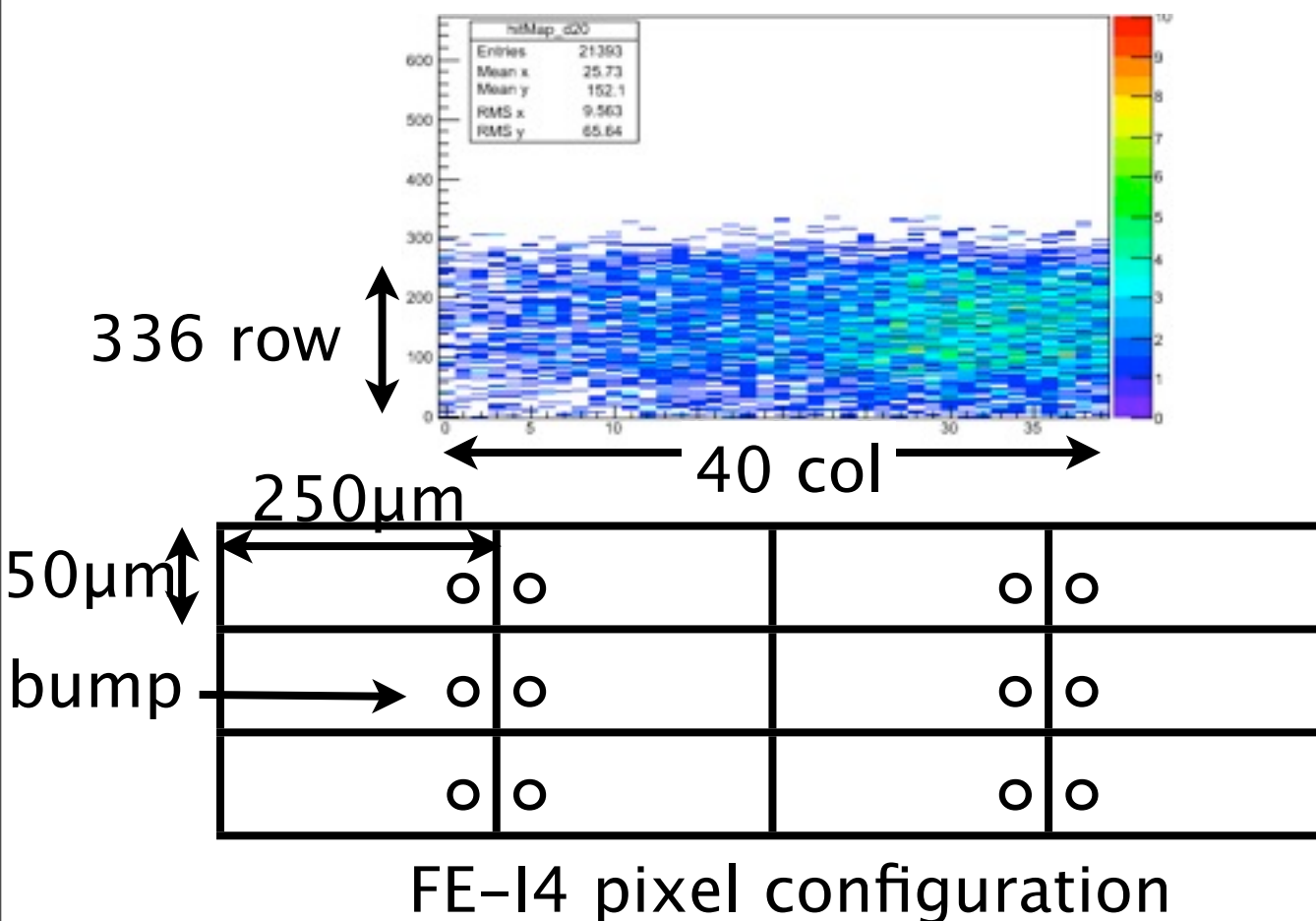
- Non-irrad. sensors
w/ $320 \mu\text{m}$ thick

6 Telescopes & 2 DUTs



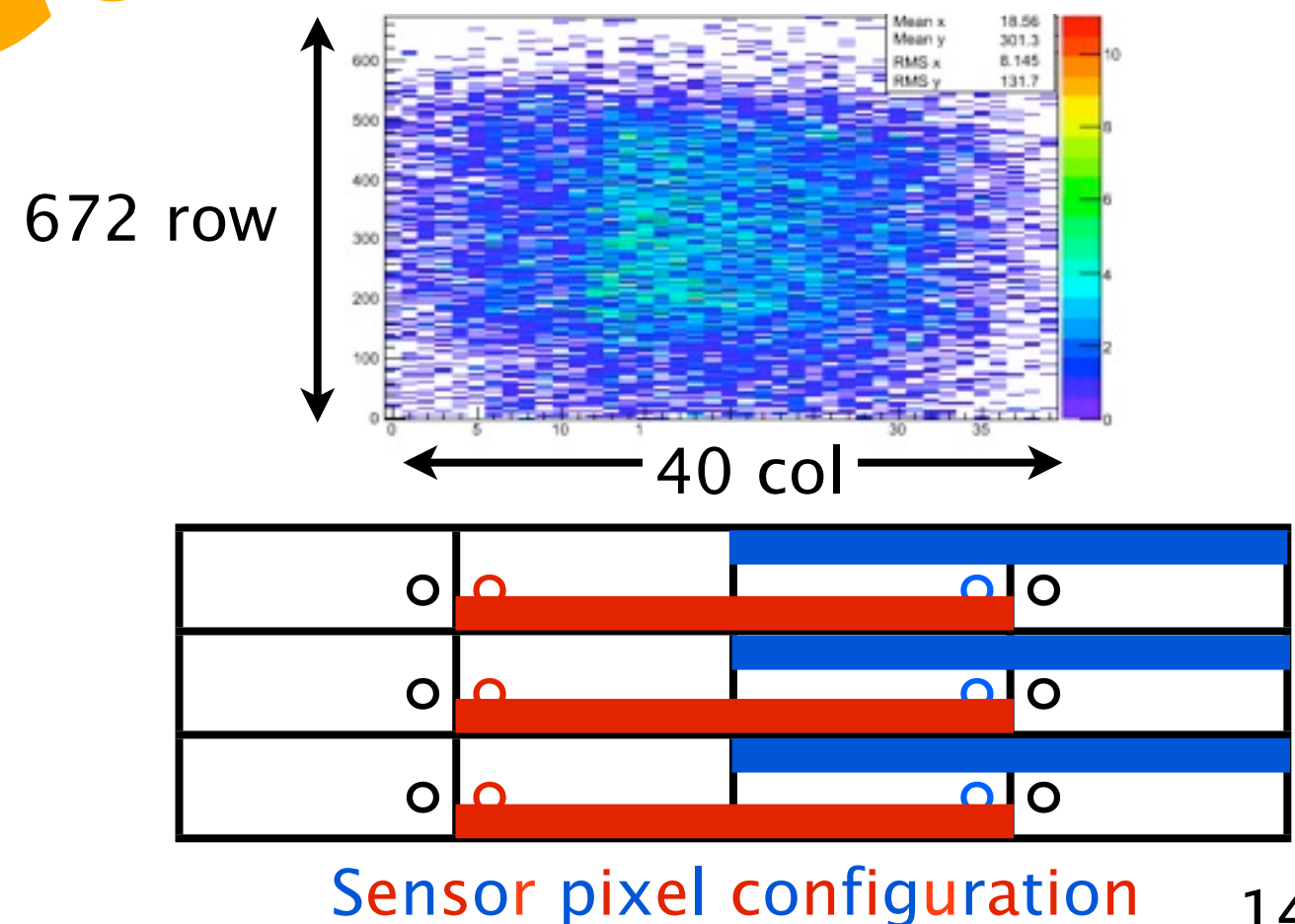
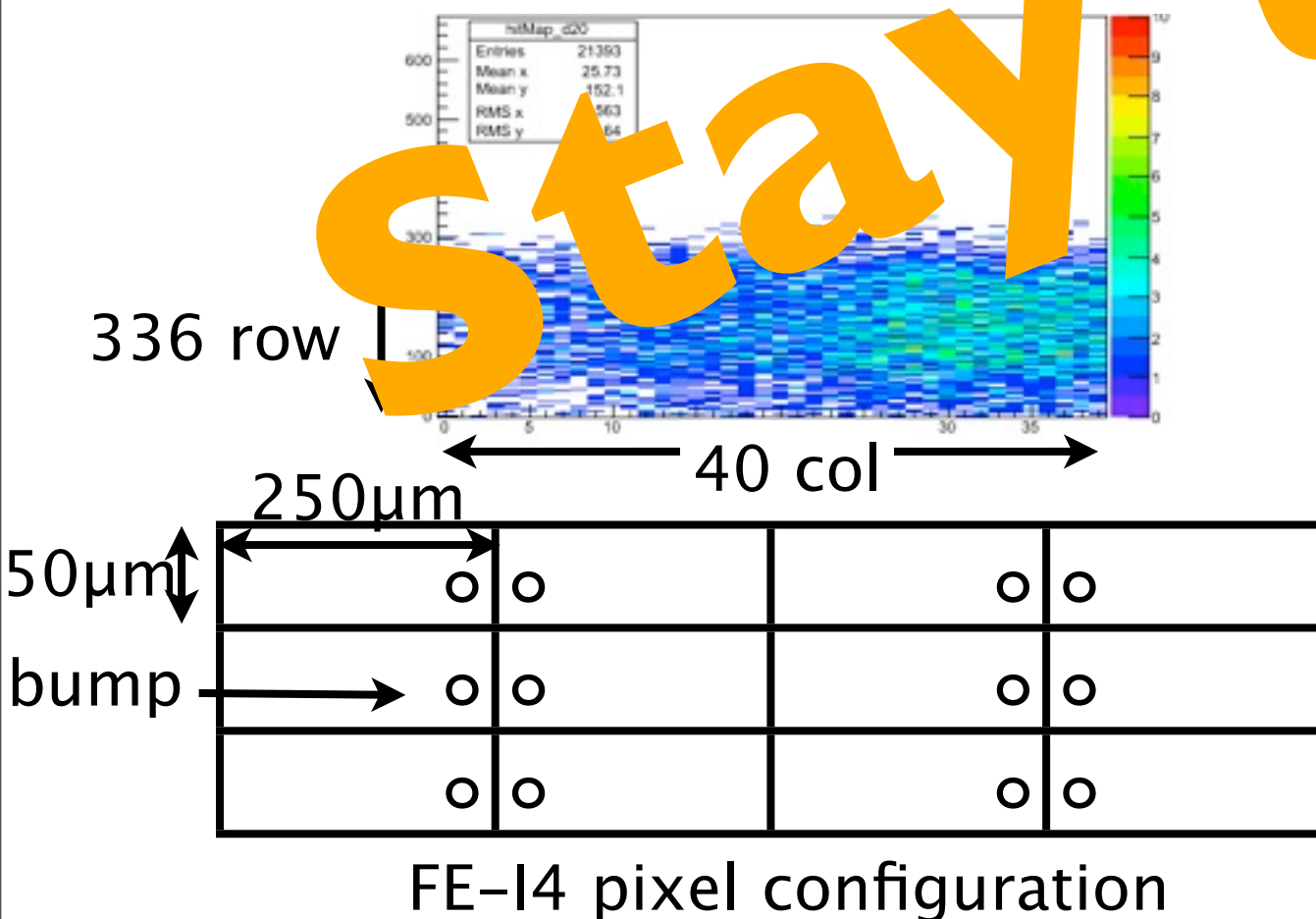
Reconstruction

- Convert FE-I4 pixel configuration (to "Long" pixel sensor)
 - FE-I4 chip: 80 col x 336 row pixels (default)
 - Long pixel sensor: 40 col x 672 row pixels
- Clustering is done with "Long" pixel, not "staggered pixel"
- Shift hit positions for odd row pixels (to "staggered" pixel)



Reconstruction

- Convert FE-I4 pixel configuration (to "Long" pixel sensor)
 - FE-I4 chip: 80 col x 336 row pixels (default)
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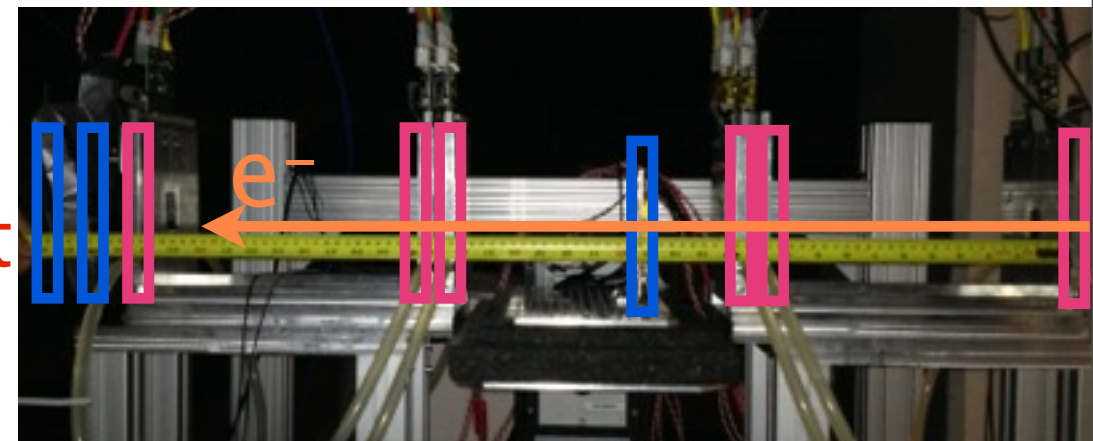


Performance at dense env.

- Evaluate performance of new pixel sensors in **dense environment**

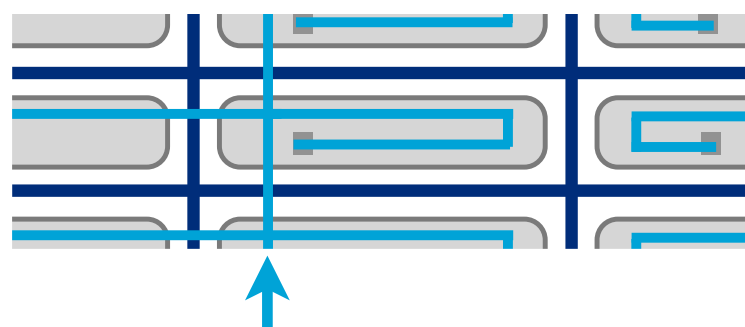
- Testbeam at SLAC in May 2014

- 2.5 GeV e^- : **~ 10 particles/event**
- 13 GeV e^- : **~ 70 particles/event**
(particles/event is measured at the most downstream telescope)

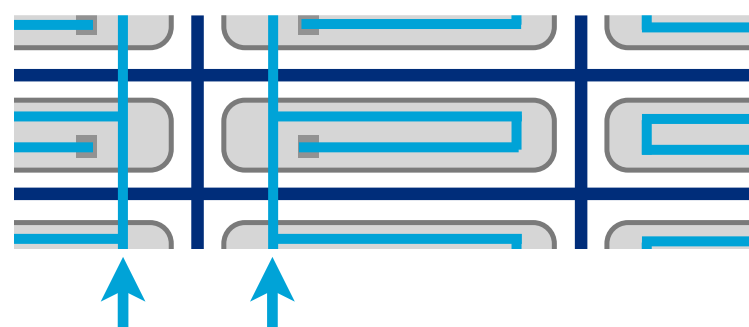


6 Telescopes
3 DUTs

- Test samples (Non-irrad. w/ 150 μm thk.)



PolySi Bias rail



PolySi Bias rail

....

- Reconstruction & Analysis are on-going

Summary

- ATLAS-J Silicon Group has developed n^+ -in-p planar pixel sensors, collaborating with Hamamatsu Photonics K.K
- Optimizing the sensor structures
- Testbeam analysis
 - Non-irrad. sensors:
uniform hit efficiency more than 99%
 - Irrad. sensors:
Hit Eff. under the bias rail is largely improved from original sensors
Especially, the offset of bias rail helps well
 - Long Staggered pixel & Evaluation in dense env.
Reconstruction and Analysis are on-going

Back Up

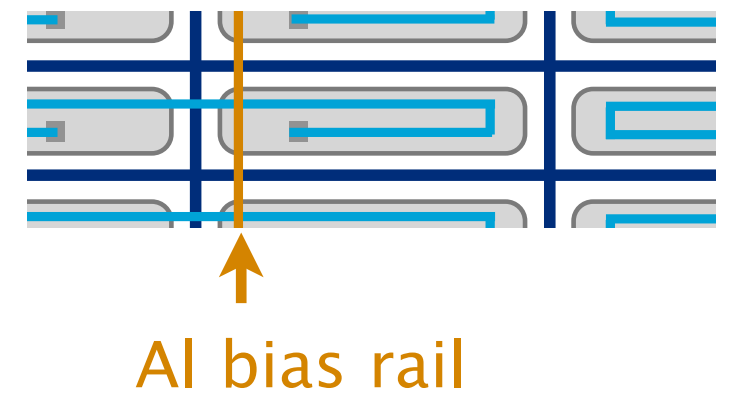
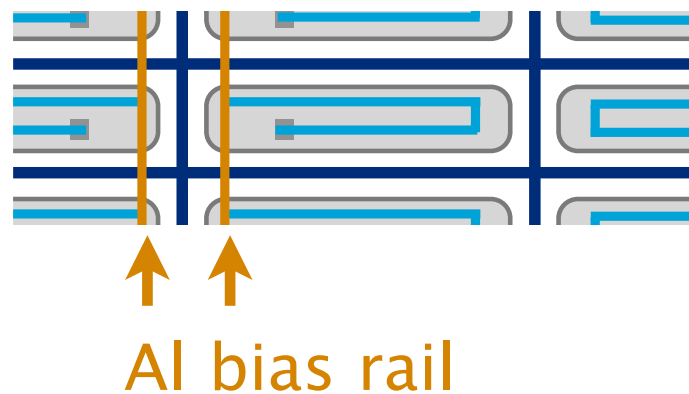
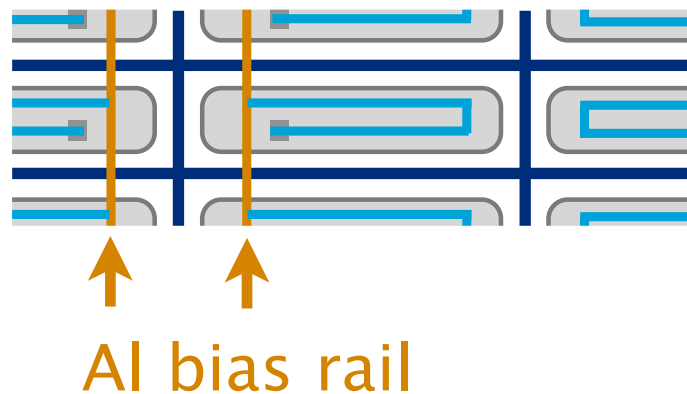
Future

■ Irradiation at CYRIC in Feb.

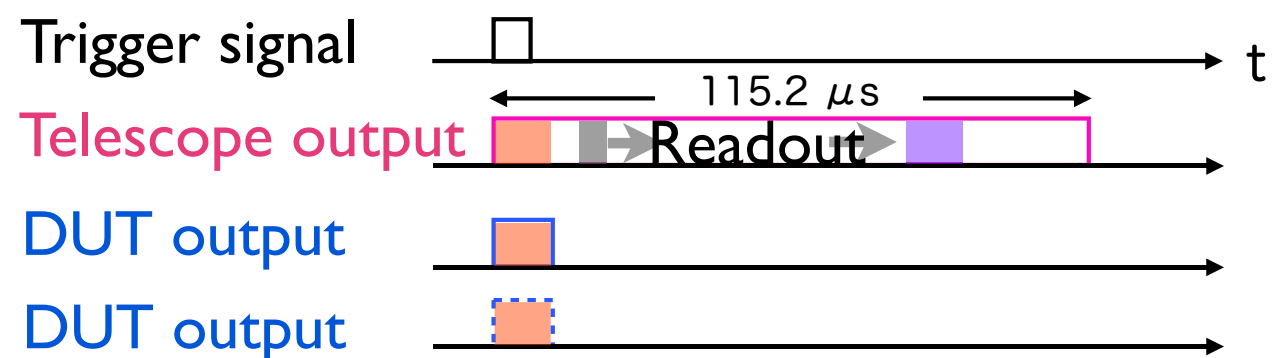
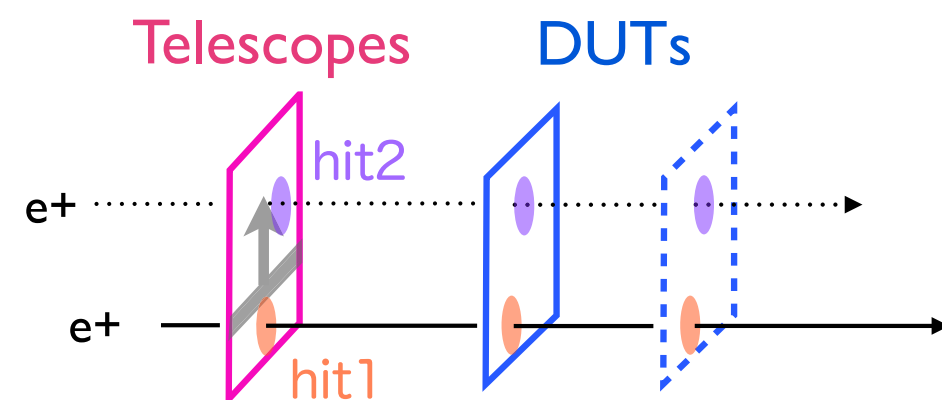
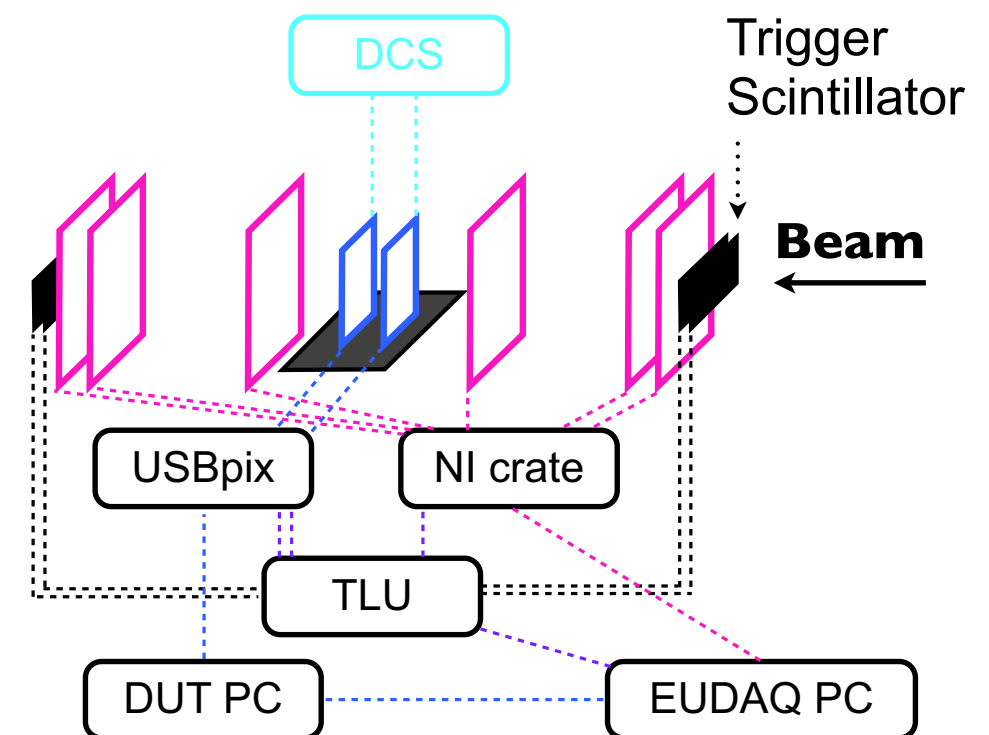
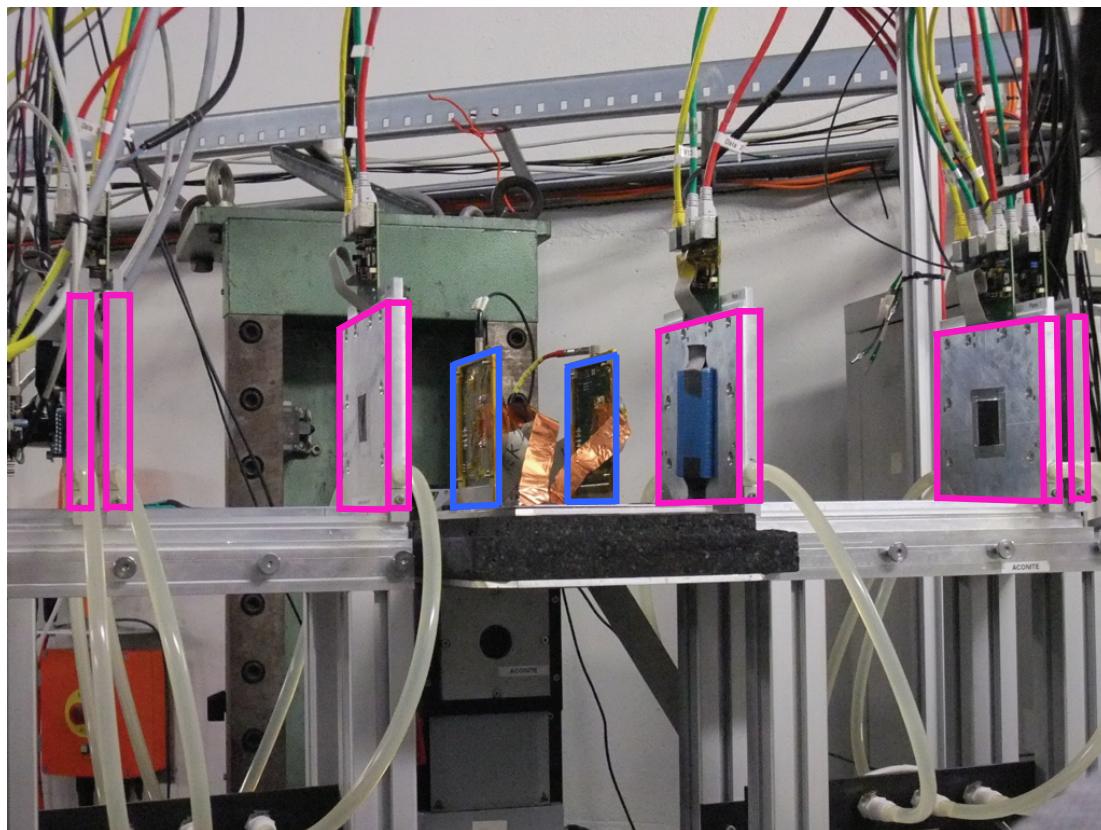
- 5 x pseudo-4chip samples w/ 150 μm thick
- Target Fluence: $3 \times 10^{15} \text{ n}_{\text{eq}} \text{ cm}^{-2}$

■ Testbeam at DESY in March

- untested irradi. sensors:



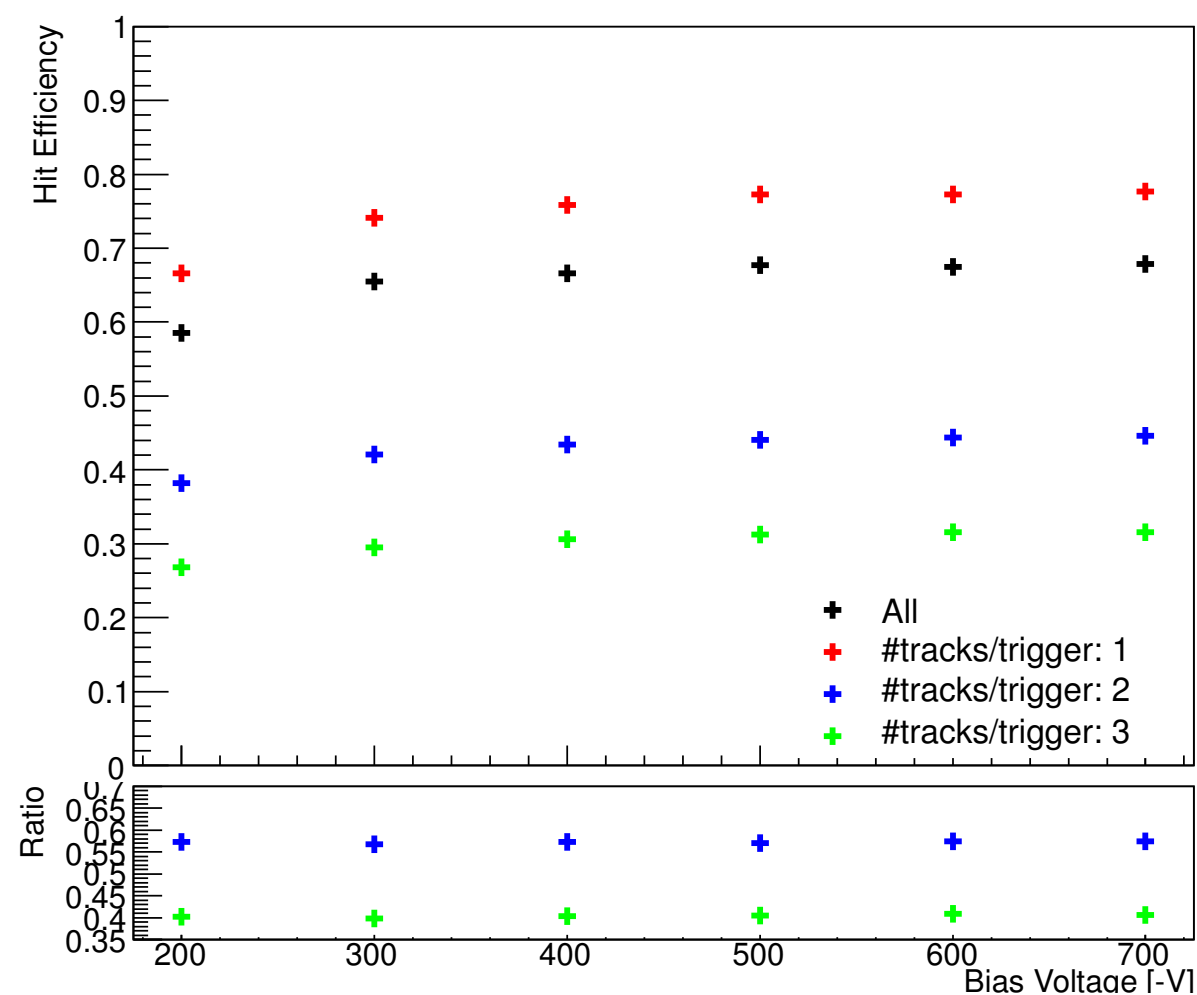
Issue about no ref. planes



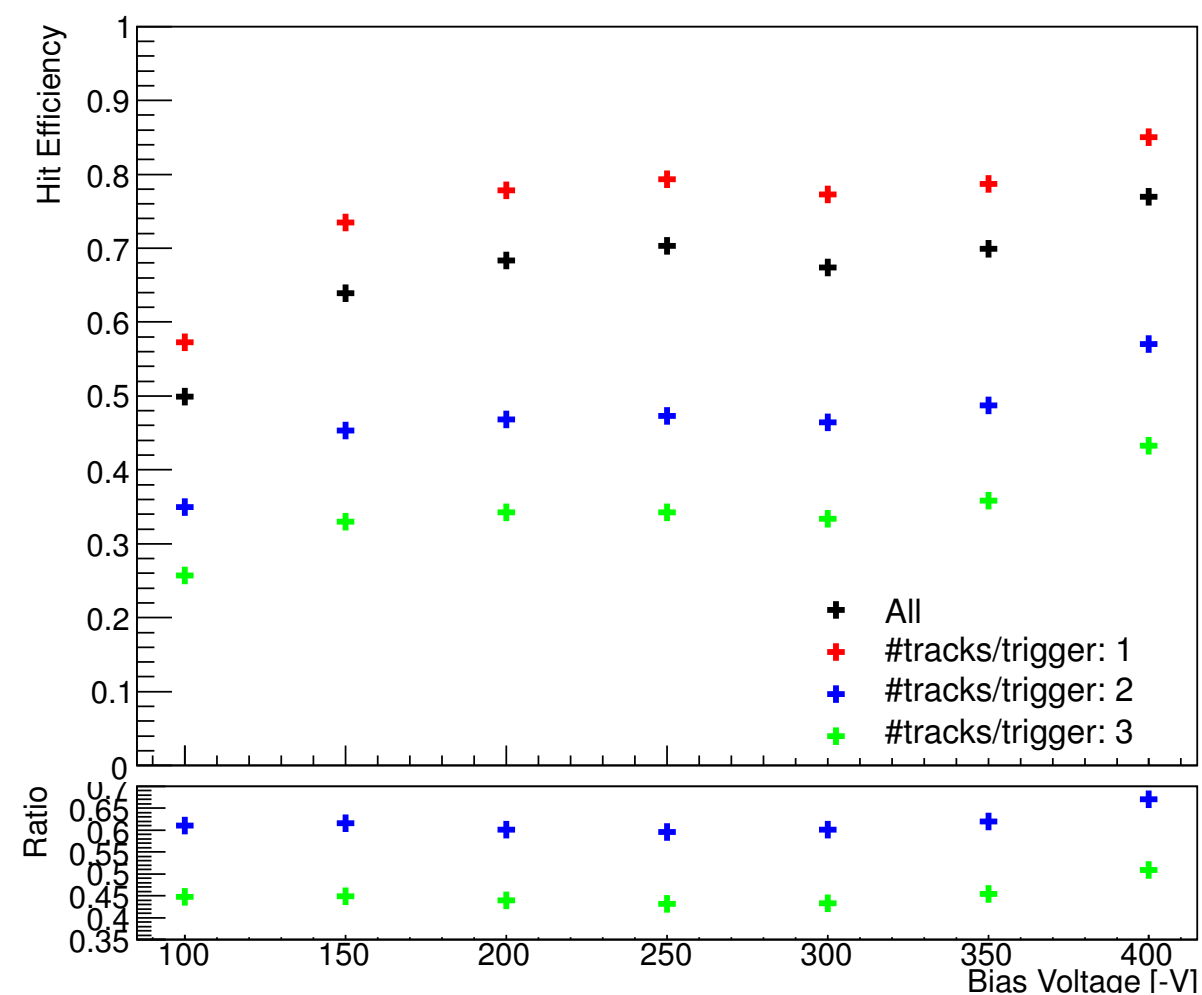
Testbeam in Nov. 2013

Without reference planes

Hit efficiency by the number of tracks per trigger



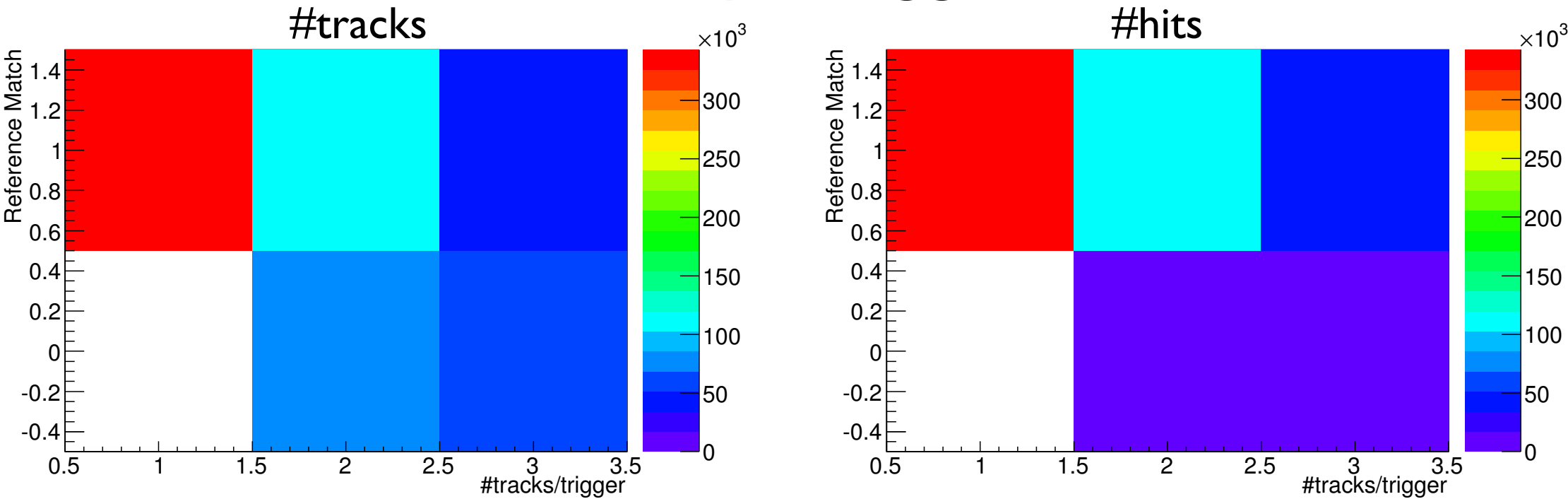
(a) KKK41



(b) KKK46 ch2

Testbeam in Feb. 2014

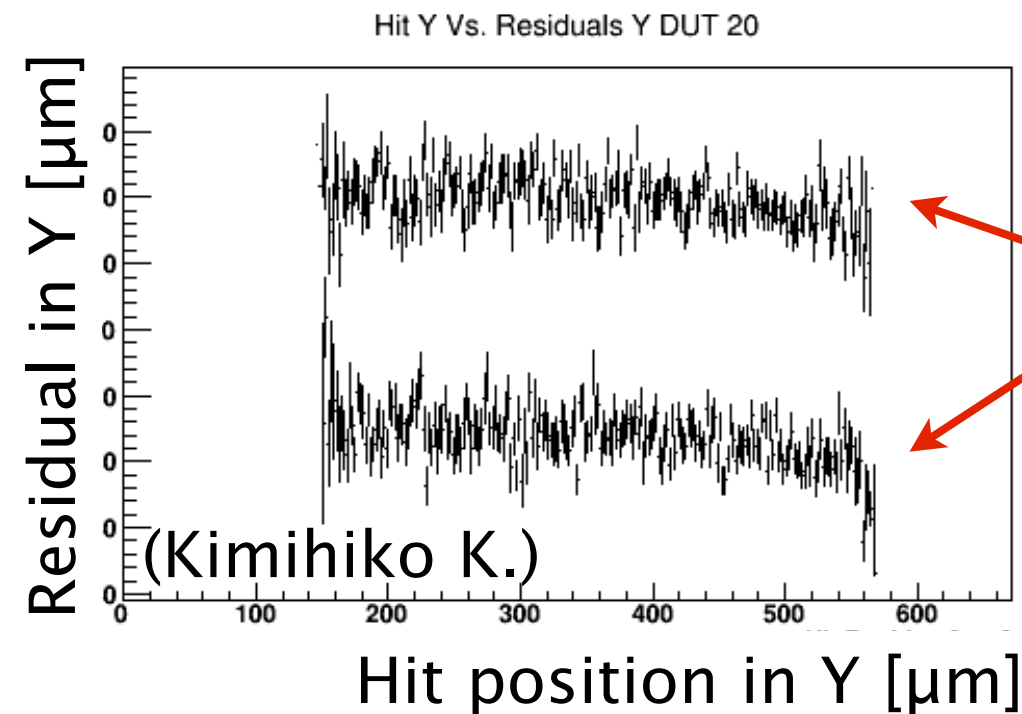
- With reference plane
- Categorize tracks by two condition:
 - exist hits on reference plane or not
 - the number of tracks per trigger



Hit Efficiency [%]	#tracks/trigger			
Ref. Match	1	2	3	sum
1	$99.88^{+0.01}_{-0.01}$	$99.81^{+0.01}_{-0.01}$	$99.75^{+0.02}_{-0.03}$	$99.85^{+0.01}_{-0.01}$
0	—	$0.014^{+0.004}_{-0.004}$	$0.009^{+0.005}_{-0.003}$	$0.013^{+0.003}_{-0.003}$
sum	$99.88^{+0.01}_{-0.01}$	$58.34^{+0.11}_{-0.11}$	$41.50^{+0.16}_{-0.16}$	$77.96^{+0.05}_{-0.05}$

Residual Problem

■ Analyzed with TBmon v2.0
and got the hit position Y vs residual Y plot below:



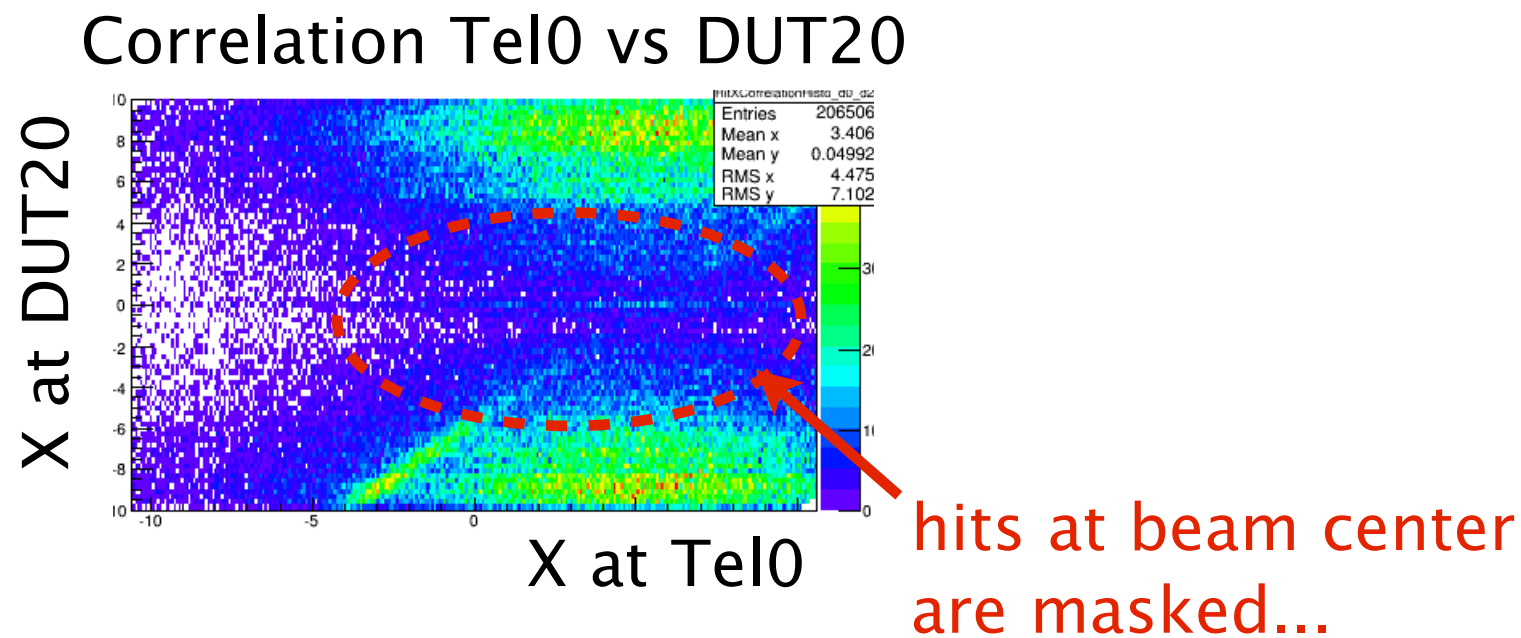
two residual values for each hit position
=> clustering or alignment problem

■ To solve this problem,
reconstruction is on-going with EUTelescope v1.0.0

- Clustering with long staggered geometry

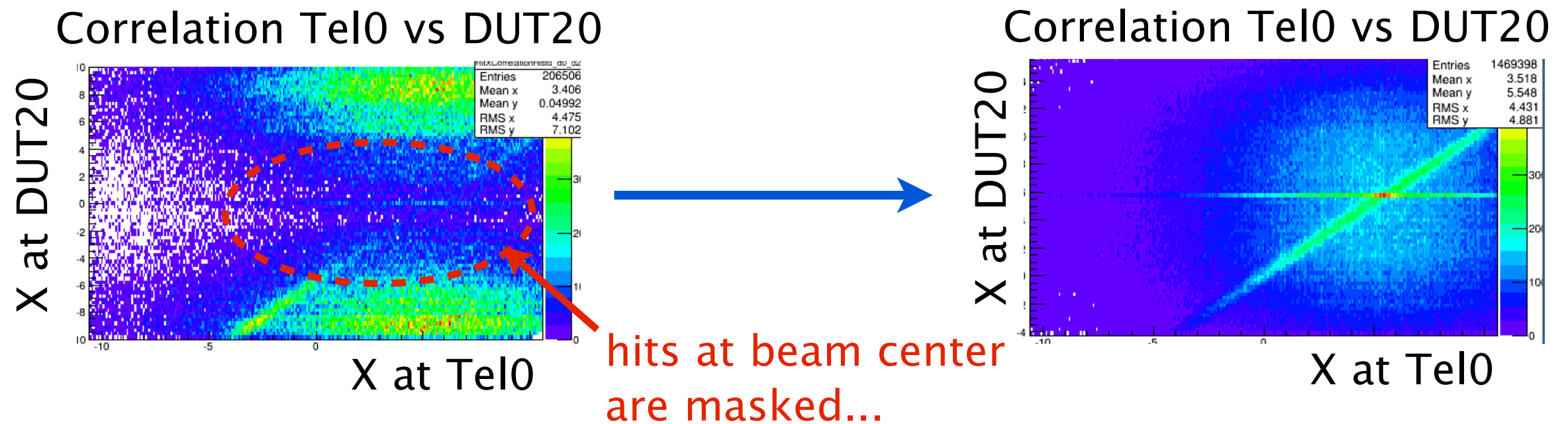
Reconstruction issue

- Recognize hits as **noise** due to very high multiplicity



Reconstruction issue

- Recognize hits as **noise** due to very high multiplicity



- Threshold to distinguish hits and noise is **set larger** (Kimihiro K.)

- Further reconstruction and analysis is on-going